

# 3.3V CMOS OCTAL BUFFER/DRIVER WITH 3-STATE OUTPUTS AND 5 VOLT TOLERANT I/O

## IDT74LVC541A

## **FEATURES:**

- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- Vcc = 3.3V ± 0.3V, Normal Range
- Vcc = 2.7V to 3.6V, Extended Range
- CMOS power levels (0.4μ W typ. static)
- · Rail-to-rail output swing for increased noise margin
- · All inputs, outputs, and I/O are 5V tolerant
- · Supports hot insertion
- · Available in QSOP package

## DRIVE FEATURES:

- · High Output Drivers: ±24mA
- · Reduced system switching noise

# **APPLICATIONS:**

- · 5V and 3.3V mixed voltage systems
- · Data communication and telecommunication systems

## **DESCRIPTION:**

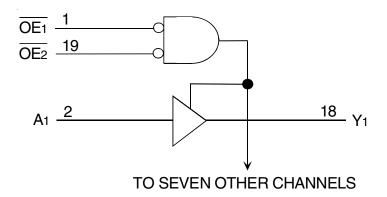
The LVC541A octal buffer/driver is built using advanced dual metal CMOS technology. This device is ideal for driving bus lines or buffer memory address registers. This device features inputs and outputs on opposite sides of the package that facilitate printed circuit board layout. The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output enable  $(\overline{OE1}$  or  $\overline{OE2}$ ) input is high, all eight outputs are in the high-impedance state.

The LVC541A has been designed with a  $\pm 24$ mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

To ensure the high-impedance state during power up or power down,  $\overline{\text{OE}}$  should be tied to Vcc through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

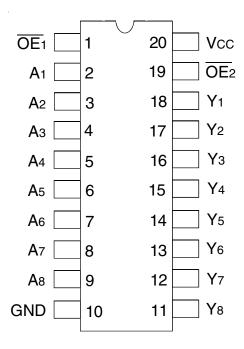
Inputs can be driven from either 3.3V or 5V devices. This feature allows the use of this device as a translator in a mixed 3.3V/5V system environment.

## **FUNCTIONAL BLOCK DIAGRAM**



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# **PIN CONFIGURATION**



QSOP TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Description	Max	Unit
VTERM	Terminal Voltage with Respect to GND	-0.5 to +6.5	V
Tstg	Storage Temperature	-65 to +150	°C
Іоит	DC Output Current	-50 to +50	mA
lik lok	Continuous Clamp Current, VI < 0 or Vo < 0	-50	mA
lcc Iss	Continuous Current through each Vcc or GND	±100	mA

#### NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

# CAPACITANCE (TA = +25°C, F = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Тур.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	4.5	6	pF
Соит	Output Capacitance	Vout = 0V	5.5	8	pF
Cı/o	I/O Port Capacitance	VIN = 0V	6.5	8	pF

#### NOTE:

1. As applicable to the device type.

# **PIN DESCRIPTION**

Pin Names	Description	
ŌĒ1, ŌĒ2	Output Enable Inputs (Active LOW)	
Ax	Data Inputs	
Yx	Data Outputs	

## FUNCTION TABLE(1)

	Outputs		
ŌĒ1	ŌĒ2	хАх	хҮх
L	L	L	L
L	L	Н	Н
Н	Х	Х	Z
Х	Н	Х	Z

## NOTE:

- 1. H = HIGH Voltage Level
  - X = Don't Care
  - L = LOW Voltage Level
  - Z = High-Impedance

# DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition:  $TA = -40^{\circ}C$  to  $+85^{\circ}C$ 

Symbol	Parameter	Test	Conditions	Min.	Typ. <sup>(1)</sup>	Max.	Unit
VIH	Input HIGH Voltage Level	Vcc = 2.3V to 2.7V		1.7	_	_	V
		Vcc = 2.7V to 3.6V		2	_	_	
VIL	Input LOW Voltage Level	Vcc = 2.3V to 2.7V		T -	_	0.7	V
		Vcc = 2.7V to 3.6V		_	_	0.8	
liH liL	Input Leakage Current	Vcc = 3.6V	VI = 0 to 5.5V	_	_	±5	μA
lozh lozl	High Impedance Output Current (3-State Output pins)	Vcc = 3.6V	Vo = 0 to 5.5V	_	_	±10	μА
loff	Input/Output Power Off Leakage	$VCC = 0V$ , $VIN or VO \le 5.5V$	1	T -	_	±50	μA
Vik	Clamp Diode Voltage	VCC = 2.3V, IIN = -18mA		T -	-0.7	-1.2	V
VH	Input Hysteresis	Vcc = 3.3V		T -	100	_	mV
ICCL ICCH	Quiescent Power Supply Current	Vcc = 3.6V	VIN = GND or Vcc	_	_	10	μA
Iccz		$3.6 \le VIN \le 5.5V^{(2)}$			_	10	
∆lcc	Quiescent Power Supply Current Variation	One input at Vcc - 0.6V, oth	er inputs at Vcc or GND	_	_	500	μA

## NOTES:

- 1. Typical values are at Vcc = 3.3V, +25°C ambient.
- 2. This applies in the disabled state only.

# **OUTPUT DRIVE CHARACTERISTICS**

Symbol	Parameter	Test Con	ditions <sup>(1)</sup>	Min.	Max.	Unit
Voн	Output HIGH Voltage	Vcc = 2.3V to 3.6V	IOH = - 0.1mA	Vcc-0.2	_	V
		Vcc = 2.3V	IOH = -6mA	2	_	
		Vcc = 2.3V	Iон = - 12mA	1.7	_	
		Vcc = 2.7V		2.2	_	
		Vcc = 3V		2.4	_	
		Vcc = 3V	Iон = - 24mA	2.2	_	
Vol	Output LOW Voltage	Vcc = 2.3V to 3.6V	IoL = 0.1mA	_	0.2	V
		Vcc = 2.3V	IoL = 6mA	_	0.4	
			IoL = 12mA	_	0.7	
		Vcc = 2.7V	IoL = 12mA	_	0.4	
		VCC = 3V	IOL = 24mA	_	0.55	

#### NOTE:

<sup>1.</sup> VIH and VIL must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate Vcc range.

TA = - 40°C to + 85°C.

# OPERATING CHARACTERISTICS, Vcc = 3.3V ± 0.3V, Ta = 25°C

Symb	bol	Parameter	Test Conditions	Typical	Unit
Срг	D	Power Dissipation Capacitance per Transceiver Outputs enabled	CL = 0pF, f = 10Mhz	33	pF
Срг	D	Power Dissipation Capacitance per Transceiver Outputs disabled		2	

# SWITCHING CHARACTERISTICS(1)

		Vcc =	2.7V	Vcc = 3.3	V ± 0.3V	
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
tplh	Propagation Delay	_	5.6	1.5	5.1	ns
tphL .	Ax to Yx					
tpzh	Output Enable Time	_	7.5	1.5	7	ns
tpzl	OEx to Yx					
tphz	Output Disable Time	_	7.7	1.5	7	ns
tplz	OEx to Yx					
tsk(o)	Output Skew <sup>(2)</sup>	_	_	_	1	ns
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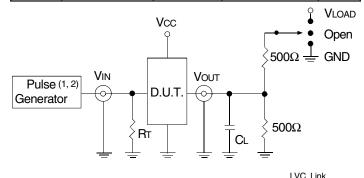
#### NOTES:

- 1. See TEST CIRCUITS AND WAVEFORMS.  $TA = -40^{\circ}C$  to  $+85^{\circ}C$ .
- 2. Skew between any two outputs of the same package and switching in the same direction.

# TEST CIRCUITS AND WAVEFORMS

## **TEST CONDITIONS**

Symbol	$Vcc^{(1)} = 3.3V \pm 0.3V$	Vcc <sup>(1)</sup> =2.7V	Vcc <sup>(2)</sup> =2.5V±0.2V	Unit
VLOAD	6	6	2 x Vcc	V
ViH	2.7	2.7	Vcc	V
VT	1.5	1.5	Vcc / 2	V
VLZ	300	300	150	mV
VHZ	300	300	150	mV
CL	50	50	30	pF



Test Circuit for All Outputs

#### **DEFINITIONS:**

CL = Load capacitance: includes jig and probe capacitance.

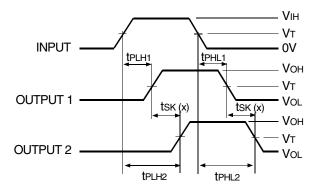
RT = Termination resistance: should be equal to ZouT of the Pulse Generator.

#### NOTES:

- 1. Pulse Generator for All Pulses: Rate  $\leq$  10MHz; tr  $\leq$  2.5ns; tr  $\leq$  2.5ns.
- 2. Pulse Generator for All Pulses: Rate  $\leq$  10MHz; tF  $\leq$  2ns; tR  $\leq$  2ns.

## **SWITCH POSITION**

Test	Switch
Open Drain Disable Low Enable Low	VLOAD
Disable High Enable High	GND
All Other Tests	Open

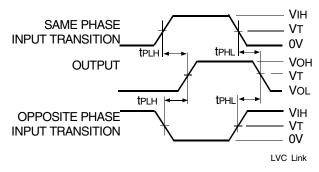


tsk(x) = |tPLH2 - tPLH1| or |tPHL2 - tPHL1|

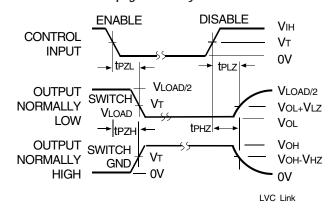
Output Skew - tsk(x) LVC Link

## NOTES:

- 1. For tsk(o) OUTPUT1 and OUTPUT2 are any two outputs.
- 2. For tsk(b) OUTPUT1 and OUTPUT2 are in the same bank.



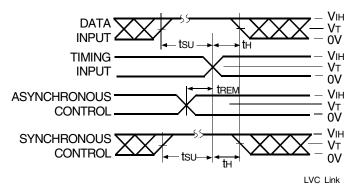
## Propagation Delay



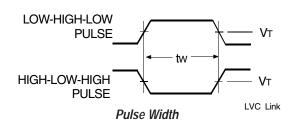
### **Enable and Disable Times**

#### NOTE:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.



Set-up, Hold, and Release Times



# ORDERING INFORMATION

